An Energy Efficient Solution by Freescale

Freeze Semiconductor Fraggie Semiconductor Constanting Community Constanting Document Number: MMA8450Q Data Sheet: Technical Data Rev. 9.1, 04/2012

RoHS

3-Axis, 8-bit/12-bit Digital Accelerometer

The MMA8450Q is a smart low-power, three-axis, capacitive micromachined accelerometer featuring 12 bits of resolution. This accelerometer is packed with embedded functions with flexible user programmable options, configurable to two interrupt pins. Embedded interrupt functions allow for overall power savings relieving the host processor from continuously polling data. The MMA8450Q's Embedded FIFO buffer can be configured to log up to 32 samples of X,Y and Z-axis 12-bit (or 8-bit for faster download) data. The FIFO enables a more efficient analysis of gestures and user programmable algorithms, ensuring no loss of data on a shared I^2C bus, and enables system level power saving (up to 96% of the total power consumption savings) by allowing the applications processor to sleep while data is logged. There is access to both low pass filtered data as well as high pass filtered data, which minimizes the data analysis required for jolt detection and faster transitions. The MMA8450Q has user selectable full scales of ±2g/±4g/±8g. The device can be configured to generate inertial wakeup interrupt signals from any combination of the configurable embedded functions allowing the MMA8450Q to monitor events and remain in a low power mode during periods of inactivity.

Features

- 1.71V to 1.89V supply voltage
- ±2g/±4g/±8g dynamically selectable full-scale
- Output Data Rate (ODR) from 400 Hz to 1.563 Hz
- 375 μ g/ \sqrt{Hz} noise at normal mode ODR = 400 Hz
- 12-bit digital output
- I2C digital output interface (operates up to 400 kHz Fast Mode)
- Programmable two interrupt pins for eight interrupt sources
- Embedded four channels of motion detection
	- Freefall or motion detection: 2 channels
		- Pulse Detection: 1 channel
		- Transient (Jolt) Detection: 1 channel
- Orientation (Portrait/Landscape) detection with hysteresis compensation
- Automatic ODR change for auto-wake and return-to-sleep
- 32 sample FIFO
- Self-Test
- 10,000g high shock survivability
- RoHS compliant

Typical Applications

- Static orientation detection (portrait/landscape, up/down, left/right, back/front position identification)
- Real-time orientation detection (virtual reality and gaming 3D user position feedback)
- Real-time activity analysis (pedometer step counting, freefall drop detection for HDD, dead-reckoning GPS backup)
- Motion detection for portable product power saving (auto-sleep and auto-wake for cell phone, PDA, GPS, gaming)
- Shock and vibration monitoring (mechatronic compensation, shipping and warranty usage logging)
- User interface (menu scrolling by orientation change, tap detection for button replacement

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Contents

Related Documentation

The MMA8450Q device features and operations are described in a variety of reference manuals, user guides, and application notes. To find the most-current versions of these documents:

1. Go to the Freescale homepage at:

<http://www.freescale.com/>

- 2. In the Keyword search box at the top of the page, enter the device number MMA8450Q.
- 3. In the Refine Your Result pane on the left, click on the Documentation link.

Figure 1. Block Diagram

1.2 Pin Description

Figure 2. Direction of the Detectable Accelerations

Figure 3 shows the device configuration in the 6 different orientation modes. These orientations are defined as the following: PU = Portrait Up, LR = Landscape Right, PD = Portrait Down, LL = Landscape Left, Back and Front. There are several registers to configure the orientation detection and are described in detail in the register setting section.

Table 1. Pin Description

When using MMA8450Q in applications, it is recommended that pin 1 and pin 14 (the VDD pins) be tied together. Power supply decoupling capacitors (100 nF ceramic plus 4.7 µF bulk, or a single 4.7 µF ceramic) should be placed as near as possible to the pins 1 and 5 of the device. The SDA and SCL l^2C connections are open drain and therefore require a pullup resistor as shown in Figure 4

Note: The above application diagram presents the recommended configuration for the MMA8450Q. For information on future products of this product family please review Freescale application note, AN3923, Design Checklist and Board Mounting Guidelines of the MMA8450Q.This application note details the small modifications between the MMA8450Q and the next generation products.

1.3 Soldering Information

The QFN package is compliant with the RoHS standard. Please refer to AN4077.

2 Mechanical and Electrical Specifications

2.1 Mechanical Characteristics

Table 2. Mechanical Characteristics @ VDD = 1.8 V, T = 25°C unless otherwise noted.

1. Before board mount.

2. See appendix for distribution graphs.

3. Post board mount offset specification are based on an 8 layer PCB.

4. Self-test in one direction only. These are approximate values and can change by ±100 counts.

2.2 Electrical Characteristics

Table 3. Electrical Characteristics @ VDD = 1.8 V, T = 25°C unless otherwise noted. **(1)**

1. Time to obtain valid data from Standby mode to Active mode.

2.3 I2C Interface Characteristic

Table 4. I2C Slave Timing Values(1)

1. All values referred to VIH (min) and VIL (max) levels.

2. t_{HD;DAT} is the data hold time that is measured from the falling edge of SCL, applies to data in transmission and the acknowledge.

3. A device must internally provide a hold time of at least 300 ns for the SDA signal (with respect to the VIH (min) of the SCL signal) to bridge the undefined region of the falling edge of SCL.

- 4. The maximum t_{HD:DAT} could be 3.45 µs and 0.9 µs for Standard-mode and Fast-mode, but must be less than the maximum of t_{VD:DAT} or t_{VD:ACK} by a transition time. This maximum must only be met if the device does not stretch the LOW period (t_{LOW}) of the SCL signal. If the clock stretches the SCL, the data must be valid by the setup time before it releases the clock.
- 5. $t_{VD:DAT}$ = time for data signal from SCL LOW to SDA output (HIGH or LOW, depending on which one is worse).

6. t_{VD:ACK} = time for Acknowledgement signal from SCL LOW to SDA output (HIGH or LOW, depending on which one is worse).

7. A Fast-mode I²C device can be used in a Standard-mode I²C system, but the requirement t_{SU;DAT} 250 ns must then be met. This will automatically be the case if the device does not stretch the LOW period of the SCL signal. If such a device does stretch the LOW period of the SCL signal, it must output the next data bit to the SDA line $t_r(max) + t_{SU;DAT} = 1000 + 250 = 1250$ ns (according to the Standard-mode I²C specification) before the SCL line is released. Also the acknowledge timing must meet this setup time

8. Cb = total capacitance of one bus line in pF.

- 9. The maximum t_f for the SDA and SCL bus lines is specified at 300 ns. The maximum fall time for the SDA output stage t_f is specified at 250 ns. This allows series protection resistors to be connected in between the SDA and the SCL pins and the SDA/SCL bus lines without exceeding the maximum specified ${\sf t}_{\sf f}.$
- 10.In Fast-mode Plus, fall time is specified the same for both output stage and bus timing. If series resistors are used, designers should allow for this when considering bus timing

Figure 5. I2C Slave Timing Diagram

2.4 Absolute Maximum Ratings

Stresses above those listed as "absolute maximum ratings" may cause permanent damage to the device. Exposure to maximum rating conditions for extended periods may affect device reliability.

Table 5. Maximum Ratings

Table 6. ESD and Latchup Protection Characteristics

This device is sensitive to mechanical shock. Improper handling can cause permanent damage of the part or cause the part to otherwise fail.

This is an ESD sensitive, improper handling can cause permanent damage to the part.

3 Terminology

3.1 Sensitivity

Sensitivity describes the gain of the sensor and can be determined by applying a g acceleration to it, such as the earth's gravitational field. The sensitivity of the sensor can be determined by subtracting the $-1g$ acceleration value from the $+1g$ acceleration value and dividing by two.

3.2 Zero-g Offset

Zero-g Offset describes the deviation of an actual output signal from the ideal output signal if no acceleration is present. A sensor in a steady state on a horizontal surface will measure 0g in X-axis and 0g in Y-axis whereas the Z-axis will measure 1g. The output is ideally in the middle of the dynamic range of the sensor (content of OUT registers 0x00, data expressed as 2's complement number). A deviation from ideal value in this case is called Zero-g offset. Offset is to some extent a result of stress on the MEMS sensor and therefore the offset can slightly change after mounting the sensor onto a printed circuit board or exposing it to extensive mechanical stress.

3.3 Self-Test

Self-Test checks the transducer functionality without external mechanical stimulus. When Self-Test is activated, an electrostatic actuation force is applied to the sensor, simulating a small acceleration. In this case the sensor outputs will exhibit a change in their DC levels which are related to the selected full scale through the device sensitivity. When Self-Test is activated, the device output level is given by the algebraic sum of the signals produced by the acceleration acting on the sensor and by the electrostatic test-force.

4 Modes of Operation

Figure 6. MMA8450Q Mode Transition Diagram

All register contents are preserved when transitioning from Active to Standby mode. Some registers are reset when transitioning from Standby to Active. These are all noted in the device memory map register table. For more detail on how to use the Sleep and Wake modes and how to transition between these modes, please refer to the functionality section of this document.

5 Functionality

The MMA8450Q is a low-power, digital output 3-axis linear accelerometer packaged in a QFN package. The complete device includes a sensing element and an IC interface able to take the information from the sensing element and to provide a signal to the external world through an I^2C serial interface. There are many embedded features in this accelerometer with a very flexible interrupt routing scheme to two interrupt pins including:

- 8-bit or 12-bit data, high pass filtered data, 8-bit or 12-bit configurable 32 sample FIFO
- Low power and Auto-Wake/Sleep for conservation of current consumption
- Single and double pulse detection 1 channel
- Motion detection and Freefall 2 channels
- Transient detection based on a high pass filter and settable threshold for detecting the change in acceleration above a threshold
- Flexible user configurable portrait landscape detection algorithm addressing many use cases for screen orientation

All functionality is available in 2g, 4g or 8g dynamic ranges. There are many configuration settings for enabling all the different functions. Separate application notes have been provided to help configure the device for each embedded functionality.

5.1 Device Calibration

The IC interface is factory calibrated for sensitivity and Zero-g offset for each axis. The trim values are stored in Non Volatile Memory (NVM). On power-up, the trim parameters are read from NVM and applied to the circuitry. In normal use, further calibration in the end application is not necessary. However, the MMA8450Q allows the user to adjust the Zero-g offset for each axis after power-up, changing the default offset values. The user offset adjustments are stored in 6 volatile registers. For more information on device calibration, refer to Freescale application note, AN3916*.*

5.2 8-bit or 12-bit Data

The measured acceleration data is stored in the OUT_X_MSB, OUT_X_LSB, OUT_Y_MSB, OUT_Y_LSB, OUT_Z_MSB, and OUT_Z_LSB registers as 2's complement 12-bit numbers. The most significant 8-bits of each axis are stored in OUT_X (Y, Z) MSB, so applications needing only 8-bit results can use these 3 registers and ignore OUT $X(Y, Z)$ LSB.

When the full-scale is set to 2g, the measurement range is -2g to +1.999g, and each LSB corresponds to $1g/1024$ (0.98 mg) at 12-bits resolution. When the full-scale is set to 8g, the measurement range is -8g to +7.996g, and each LSB corresponds to 1g/256 (3.9 mg) at 12-bits resolution. The resolution is reduced by a factor of 16 if only the 8-bit results are used. For more information on the data manipulation between data formats and modes, refer to Freescale application note, AN3922. There is a device driver available that can be used with the Sensor Toolbox demo board (LFSTBEB8450Q) with this application note.

5.3 Internal FIFO Data Buffer

MMA8450Q contains a 32 sample internal FIFO data buffer minimizing traffic across the I²C bus. The FIFO can also provide power savings of the system by allowing the host processor/MCU to go into a sleep mode while the accelerometer independently stores the data, up to 32 samples per axis. The FIFO can run at all output data rates. There is the option of accessing the full 12 bit data for accessing only the 8-bit data. When access speed is more important than high resolution the 8-bit data flush is a better option.

The FIFO contains three modes (Fill Buffer Mode, Circular Buffer Mode, and Disabled) described in the F_SETUP Register 0x13. Fill Buffer Mode collects the first 32 samples and asserts the overflow flag when the buffer is full. It does not collect anymore data until the buffer is read. This benefits data logging applications where all samples must be collected. The Circular Buffer Mode allows the buffer to be filled and then new data replaces the oldest sample in the buffer. The most recent 32 samples will be stored in the buffer. This benefits situations where the processor is waiting for an specific interrupt to signal that the data must be flushed to analyze the event.

The MMA8450Q FIFO Buffer also has a configurable watermark, allowing the processor to be interrupted after a configurable number of samples has filled in the buffer (1 to 32).

For details on the configurations for the FIFO Buffer as well as more specific examples and application benefits, refer to Freescale application note, AN3920*.*

5.4 Low Power Mode

The MMA8450Q can be set to a low power mode to further reduce the current consumption of the device. When the Low Power Mode is enabled, the device has access to all the configurable sampling rates and features as is available in the Normal power mode. To set the device into Low Power Mode, bit 0 in the System Control Register 2 (0x39) should be set (1) (this bit is cleared (0) for Normal Power Mode). Low Power Mode reduces the current consumption by internally sleeping longer and averaging the data less. The Low Power Mode is an additional feature that is independent of the sleep feature.The sleep feature can also be used to reduce the current consumption by automatically changing to a lower sample rate when no activity is detected.

For more information on how to configure the MMA8450Q in Low Power Mode and the power consumption benefits of Low Power Mode and Auto-Wake/Sleep with specific application examples, refer to Freescale application note, AN3921.

5.5 Auto-Wake/Sleep Mode

The MMA8450Q can be configured to transition between sample rates (with their respective current consumption) based on five of the interrupt functions of the device. The advantage of using the Auto-Wake/Sleep is that the system can automatically transition to a higher sample rate (higher current consumption) when needed but spends the majority of the time in the Sleep Mode (lower current) when the device does not require higher sampling rates. Auto-Wake refers to the device being triggered by one of the interrupt functions to transition to a higher sample rate. This may also interrupt the processor to transition from a sleep mode to a higher power mode.

Sleep Mode occurs after the accelerometer has not detected an interrupt for longer than the user definable timeout period. The device will transition to the specified lower sample rate. It may also alert the processor to go into a lower power mode to save on current during this period of inactivity.

The Interrupts that can wake the device from sleep are the following: Tap Detection, Orientation Detection, Motion/Freefall1, Motion/Freefall2, and Transient Detection. The FIFO can be configured to hold the data in the buffer until it is flushed if the FIFO Gate bit is set in Register 0x3A but the FIFO cannot wake the device from sleep.

The interrupts that can keep the device from falling asleep are the same interrupts that can wake the device with the addition of the FIFO. If the FIFO interrupt is enabled and data is being accessed continually servicing the interrupt then the device will remain in the wake mode. Refer to AN3921, for more detailed information for configuring the Auto-Wake/Sleep and for application examples of the power consumption savings.

5.6 Freefall and Motion Detection

MMA8450Q has flexible interrupt architecture for detecting Freefall and Motion with the two Motion/Freefall interrupt functions available. With two configurable interrupts for Motion and Freefall, one interrupt can be configured to detect a linear freefall while the other can be configured to detect a spin motion. The combination of these two events can be routed to separate interrupts or to the same interrupt pin to detect tumble which is the combination of spin with freefall. For details on the advantages of having the two embedded functions of Freefall and Motion detection with specific application examples with recommended configuration settings, refer to Freescale application note AN3917.

5.6.1 Freefall Detection

The detection of "Freefall" involves the monitoring of the X, Y, and Z axes for the condition where the acceleration magnitude is **below** a user specified threshold for a user definable amount of time. Normally the usable threshold ranges are between $±0$ mg and $±500$ mg.

5.6.2 Motion Detection

There are two programmable functions for motion (MFF1 and MFF2). Motion is configured using the high-g mechanism. Motion is often used to simply alert the main processor that the device is currently in use. When the acceleration exceeds a set threshold the motion interrupt is asserted. A motion can be a fast moving shake or a slow moving tilt. This will depend on the threshold and timing values configured for the event. The motion detection function can analyze static acceleration changes or faster jolts. For example, to detect that an object is spinning, all three axes would be enabled with a threshold detection of > 2g. This condition would need to occur for a minimum of 100 ms to ensure that the event wasn't just noise. The timing value is set by a configurable debounce counter. The debounce counter acts like a filter to determine whether the condition exists for configurable set of time (i.e., 100 ms or longer).

5.7 Transient Detection

The MMA8450Q has a built in high pass filter. Acceleration data goes through the high pass filter, eliminating the offset (DC) and low frequencies. The high pass filter cutoff frequency can be set by the user to four different frequencies which are dependent on the Output Data Rate (ODR). A higher cutoff frequency ensures the DC data or slower moving data will be filtered out, allowing only the higher frequencies to pass. The embedded Transient Detection function uses the high pass filtered data allowing the user to set the threshold and debounce counter.

Many applications use the accelerometer's static acceleration readings (i.e., tilt) which measure the change in acceleration due to gravity only. These functions benefit from acceleration data being filtered from a low pass filter where high frequency data is considered noise. However, there are many functions where the accelerometer must analyze dynamic acceleration. Functions such as tap, flick, shake and step counting are based on the analysis of the change in the acceleration. It is simpler to interpret these functions dependent on dynamic acceleration data when the static component has been removed. The Transient Detection function can be routed to either interrupt pin through bit 5 in CTRL_REG5 Register (0x3C). Registers 0x2B – 0x2E are the dedicated Transient Detection configuration registers. For details on the benefits of the embedded Transient Detection function along with specific application examples and recommended configuration settings, please refer to Freescale application note, AN3918.

5.8 Orientation Detection

The MMA8450Q incorporates an advanced algorithm for orientation detection (ability to detect all 6 orientations including portrait/landscape) with a large amount of configuration available to provide extreme flexibility to the system designer. The configurability also allows for the function to work differently for various modes of the end system. For example, the MMA8450Q Orientation Detection allows up to 10 selectable trip angles for Portrait-to-Landscape, up to10 selectable trip angles for the transition for Landscape-to-Portrait, and 4 selectable front/back trip angles. Typically the desired hysteresis angle is ±15° from a 45° trip reference point, resulting in |30°| and |60°| trip points. The algorithm is robust enough to handle typical process variation and uncompensated board mount offset, however, it may result in slight angle variations.

The MMA8450Q Orientation Detection algorithm confirms the reliability of the function with a configurable Z-lockout angle. Based on known functionality of linear accelerometers, it is not possible to rotate the device about the Z-axis to detect change in acceleration at slow angular speeds. The angle at which the image no longer detects the orientation change is referred to as the "Z-Lockout angle". The MMA8450Q Orientation Detection function has eight selectable1g-lockout thresholds; and there are 8 different settings for the Z-Angle lockout.

The Orientation Detection function also considers when a device is experiencing acceleration above a set threshold not typical of orientation changes (i.e., When a person is jogging or due to acceleration changes from being on a bus or in a car). The screen orientation should not interpret this as a change and the screen should lock in the last known valid position. This added feature, called the 1g Lockout Threshold, enhances the Orientation Detection function and confirms the reliability of the algorithm for the system. The MMA8450Q allows for configuring the 1g Lockout Threshold from 1g up to 1.35g (in increments of 0.05g).

For further information on the highly configurable embedded Orientation Detection Function, including recommendations for configuring the device to support various application use cases, refer to Freescale application note, AN3915*.*

Figure 7 and Figure 8 show the definitions of the trip angles going from Landscape-to-Portrait and then also from Portrait-to-Landscape.

Figure 7. Illustration of Landscape-to-Portrait Transition Figure 8. Illustration of Portrait-to-Landscape Transition

Figure 9 illustrates the Z-angle lockout region. When lifting the device up from the flat position it will be active for orientation detection as low as 25° from flat. This is user configurable. The default angle is 32° but it can be set as low as 25°.

Figure 9. Illustration of Z-Tilt Angle Lockout Transition

5.9 Interrupt Register Configurations

There are eight configurable interrupts in the MMA8450Q. These are Auto-Sleep, FIFO, Transient Detect, Orientation Detect, Pulse Detect, Freefall/Motion, and the Data Ready events. These eight interrupt sources can be routed to one of two interrupt pins. The interrupt source must be enabled and configured. If the event flag is asserted because the event condition is detected, the corresponding interrupt pin, INT1 or INT2, will assert.

Figure 10. System Interrupt Generation Block Diagram

5.10 Serial I2C Interface

Acceleration data may be accessed through an $1²C$ interface thus making the device particularly suitable for direct interfacing with a microcontroller. The MMA8450Q features an interrupt signal which indicates when a new set of measured acceleration data is available thus simplifying data synchronization in the digital system that uses the device. The MMA8450Q may also be configured to generate other interrupt signals accordingly to the programmable embedded functions of the device for Motion, Freefall, Transient, Orientation, and Tap.

The registers embedded inside MMA8450Q are accessed through an I²C serial interface. The EN pin is controlled by the MCU I/O pin to be either high or low, depending on the desired state. To enable the I^2C interface, the EN pin (pin 8) must be tied high. When EN is tied low, MMA8450Q is put into low power shutdown mode and communications on the I²C interface are ignored. The MMA8450Q is always in slave mode. The I²C interface may be used for communications between other I²C devices when EN is tied low and the MMA8450Q does not clamp the $I²C$ bus.

Table 8. Serial Interface Pin Description

There are two signals associated with the I²C bus; the Serial Clock Line (SCL) and the Serial Data line (SDA). The latter is a bidirectional line used for sending and receiving the data to/from the interface. External 4.7 kΩ pullup resistors connected to VDD are expected for SDA and SCL. When the bus is free both the lines are high. The I²C interface is compliant with fast mode (400 kHz), and normal mode (100 kHz) I²C standards (Table 4).

5.10.1 I2C Operation

The transaction on the bus is started through a start condition (START) signal. START condition is defined as a HIGH to LOW transition on the data line while the SCL line is held HIGH. After START has been transmitted by the Master, the bus is considered busy. The next byte of data transmitted after START contains the slave address in the first 7 bits, and the eighth bit tells whether the Master is receiving data from the slave or transmitting data to the slave. When an address is sent, each device in the system compares the first seven bits after a start condition with its address. If they match, the device considers itself addressed by the Master. The 9th clock pulse, following the slave address byte (and each subsequent byte) is the acknowledge (ACK). The transmitter must release the SDA line during the ACK period. The receiver must then pull the data line low so that it remains stable low during the high period of the acknowledge clock period.

The number of bytes transferred per transfer is unlimited. If a receiver can't receive another complete byte of data until it has performed some other function, it can hold the clock line, SCL low to force the transmitter into a wait state. Data transfer only continues when the receiver is ready for another byte and releases the data line. This delay action is called clock stretching.

A LOW to HIGH transition on the SDA line while the SCL line is high is defined as a stop condition (STOP). A data transfer is always terminated by a STOP. A Master may also issue a repeated START during a data transfer. The MMA8450Q expects repeated STARTs to be used to randomly read from specific registers.

The MMA8450Q's standard slave address is a choice between the two sequential addresses 0011100 and 0011101. The selection is made by the high and low logic level of the SA0 (pin 7) input respectively. The slave addresses are factory programmed and alternate addresses are available at customer request. The format is shown in Table 9.

Table 9. I2C Address Selection Table

Single Byte Read

The MMA8450Q has an internal ADC that can sample, convert and return sensor data on request. The transmission of an 8-bit command begins on the falling edge of SCL. After the eight clock cycles are used to send the command, note that the data returned is sent with the MSB first once the data is received. Figure 11 shows the timing diagram for the accelerometer 8-bit ${}^{12}C$ read operation. The Master (or MCU) transmits a start condition (ST) to the MMA8450Q, slave address (\$1D), with the R/W bit set to "0" for a write, and the MMA8450Q sends an acknowledgement. Then the Master (or MCU) transmits the address of the register to read and the MMA8450Q sends an acknowledgement. The Master (or MCU) transmits a repeated start condition (SR) and then addresses the MMA8450Q (\$1D) with the R/W bit set to "1" for a read from the previously selected register. The Slave then acknowledges and transmits the data from the requested register. The Master does not acknowledge (NAK) it received the transmitted data, but transmits a stop condition to end the data transfer.

Multiple Byte Read

When performing a multibyte read or "burst read", the MMA8450Q automatically increments the received register address commands after a read command is received. Therefore, after following the steps of a single byte read, multiple bytes of data can be read from sequential registers after each MMA8450Q acknowledgment (AK) is received until a NACK is received from the Master followed by a stop condition (SP) signaling an end of transmission.

Single Byte Write

To start a write command, the Master transmits a start condition (ST) to the MMA8450Q, slave address (\$1D) with the R/W bit set to "0" for a write, the MMA8450Q sends an acknowledgement. Then the Master (MCU) transmits the address of the register to write to, and the MMA8450Q sends an acknowledgement. Then the Master (or MCU) transmits the 8-bit data to write to the designated register and the MMA8450Q sends an acknowledgement that it has received the data. Since this transmission is complete, the Master transmits a stop condition (SP) to the data transfer. The data sent to the MMA8450Q is now stored in the appropriate register.

Multiple Byte Write

The MMA8450Q automatically increments the received register address commands after a write command is received. Therefore, after following the steps of a single byte write, multiple bytes of data can be written to sequential registers after each MMA8450Q acknowledgment (ACK) is received.

Table 10. I2C device Address Sequence

< Single Byte Read >

Figure 11. I2C Timing Diagram

6 Register Descriptions

Table 11 is the memory map of the MMA8450Q.The user has access to all addresses from 0x00 to 0x3F. **Note:** There are no differences between the MSBs located in 0x01, 0x02, 0x03 and 0x06, 0x08, 0x0A.

Table 11. Register Address Map

Table 11. Register Address Map

1. Register contents are preserved when transition from "ACTIVE" to "STANDBY" mode occurs.

2. Register contents are reset when transition from "STANDBY" to "ACTIVE" mode occurs.

3. Modification of this register's contents can only occur when device is "STANDBY" mode

4. Register contents can be modified anytime in "STANDBY" or "ACTIVE" mode. A write to this register will cause a reset of the corresponding internal system debounce counter.

Note: Auto-increment addresses which are not a simple increment are highlighted in **bold**. The auto-increment addressing is only enabled when device registers are read using I²C burst read mode. Therefore the internal storage of the auto-increment address is clear whenever a stop-bit is detected.

6.1 Data Registers

The following are the data registers for the MMA8450Q. For more information on data manipulation of the MMA8450Q, refer to application note, AN3922*.*

0x00, 0x04, 0x0B: STATUS Registers

. **Alias for DR_Status (0x0B) or F_Status (0x10) (Read Only)**

When FDE bit found in register 0x16 (XYZ_DATA_CFG), bit 7 is cleared (the FIFO is not on) register 0x00, 0x04 and 0x0B should all be the same value and reflect the real-time status information of the X, Y and Z sample data. When FDE is set (the FIFO is on) Register 0x00, 0x04 and 0x10 will have the same value and 0x0B will reflect the status of the transient data. The aliases allow the STATUS register to be read easily before reading the current 8-bit, 12-bit, or FIFO sample data using the register address auto-incrementing mechanism.

0X00, 0X04, 0X0B STATUS: Data Status Registers (Read Only)

Table 12. STATUS Description

ZYXOW is set whenever a new acceleration data is produced before completing the retrieval of the previous set. This event occurs when the content of at least one acceleration data register (i.e., OUT_X, OUT_Y, OUT_Z) has been overwritten. ZYXOW is cleared when the high-bytes of the acceleration data (OUT_X_MSB, OUT_Y_MSB, OUT_Z_MSB) of all the active channels are read.

ZOW is set whenever a new acceleration sample related to the Z-axis is generated before the retrieval of the previous sample. When this occurs the previous sample is overwritten. ZOW is cleared anytime OUT_Z_MSB register is read.

YOW is set whenever a new acceleration sample related to the Y-axis is generated before the retrieval of the previous sample. When this occurs the previous sample is overwritten. YOW is cleared anytime OUT_Y_MSB register is read.

XOW is set whenever a new acceleration sample related to the X-axis is generated before the retrieval of the previous sample. When this occurs the previous sample is overwritten. XOW is cleared anytime OUT_X_MSB register is read.

ZYXDR signals that a new sample for any of the enabled channels is available. ZYXDR is cleared when the high-bytes of the acceleration data (OUT_X_MSB, OUT_Y_MSB, OUT_Z_MSB) of all the enabled channels are read.

ZDR is set whenever a new acceleration sample related to the Z-axis is generated. ZDR is cleared anytime OUT_Z_MSB register is read. In order to enable the monitoring and assertion of this bit, the ZDR bit requires the Z-axis event detection flag to be enabled (bit ZDEFE = 1 inside XYZ_DATA_CFG register).

YDR is set whenever a new acceleration sample related to the Y-axis is available. YDR is cleared anytime OUT_Y_MSB register is read. In order to enable the monitoring and assertion of this bit, the YDR bit requires the Y-axis event detection flag to be enabled (bit YDEFE = 1 inside XYZ_DATA_CFG register).

XDR is set to 1 whenever a new acceleration sample related to the X-axis is available. XDR is cleared anytime OUT X MSB register is read. In order to enable the monitoring and assertion of this bit, the XDR bit requires the X-axis to event detection flag to be enabled (bit $XDEFE = 1$ inside XYZ DATA CFG register).

The **ZDR** and **ZOW** flag generation requires the Z-axis event flag generator to be enabled (ZDEFE = 1) in the XYZ_DATA_CFG register.

The **YDR** and **YOW** flag generation requires the Y-axis event flag generator to be enabled (YDEFE = 1) in the XYZ_DATA_CFG register.

The **XDR** and **XOW** flag generation requires the X-axis event flag generator to be enabled (XDEFE = 1) in the XYZ_DATA_CFG register.

The **ZYXDR** and **ZYXOW** flag generation is requires the Z-axis, Y-axis, X-axis event flag generator to be enabled (ZDEFE = 1, YDEFE = 1, $XDEFE = 1$) in the XYZ_DATA_CFG register.

0x01, 0x02, 0x03: OUT_MSB 8-Bit XYZ Data Registers

X, Y and Z-axis data is expressed as 2's complement numbers. The most significant 8-bits are stored together in OUT_X_MSB, OUT_Y_MSB, OUT_Z_MSB so applications needing only 8-bit results can use these registers and can ignore the OUT_X_LSB, OUT_Y_LSB, OUT_Z_LSB. The status Register 0x00, OUT_X_MSB, OUT_Y_MSB, OUT_Z_MSB are duplicated in the auto-incrementing address range of 0x00 to 0x03 to reduce reading the status followed by 8-bit axis data to a 4 byte sequence.

0x01 OUT_X_MSB: X_MSB Register (Read Only)

0x02 OUT_Y_MSB: Y_MSB Register (Read Only)

0x03 OUT_Z_MSB: Z_MSB Register (Read Only)

0x05 - 0x0A: OUT_MSB and OUT_LSB 12-Bit XYZ Data Registers

X, Y and Z-axis data is expressed as 2's complement numbers. The STATUS (0x04), OUT_X_LSB (0x05), OUT_X_MSB (0x06), OUT_Y_LSB (0x07), OUT_Y_MSB (0x08), OUT_Z_LSB(0x09), OUT_Z_MSB (0x0A) are stored in auto-incrementing address range of 0x04 to 0x0A to reduce reading the status followed by 12-bit axis data to 7 bytes.

0x05 OUT_X_LSB: X_LSB Register (Read Only)

0x06 OUT_X_MSB: X_MSB Register (Read Only)

0x07 OUT_Y_LSB: Y_LSB Register (Read Only)

0x08 OUT_Y_MSB: Y_MSB Register (Read Only)

0x09 OUT_Z_LSB: Z_LSB Register (Read Only)

0x0A OUT_Z_MSB: Z_MSB Register (Read Only)

The sample data output registers store the current sample data if the FIFO data output register driver is disabled, but if the FIFO data output register driver is enabled, the 12 sample data output registers point to the head of the FIFO buffer which contains the previous 32 X, Y, and Z data samples. This applies for the 8-bit data and the 12-bit data.

When the FDE bit is set to logic 1, the F_8DATA (0x11) FIFO root data pointer shares the same address location as the OUT_X_MSB register (0x01); therefore all 8-bit accesses of the FIFO buffer data must use the $I²C$ address 0x01. The F_12DATA $(0x12)$ FIFO root data pointer shares the same address location as the OUT_X_LSB register $(0x05)$; therefore all 12-bit accesses of the FIFO buffer data must use the I²C address 0x05. All reads to register addresses 0x02, 0x03, 0x06, 0x07, 0x08, 0x09, and 0x0A returns a value of 0x00.

0x0C - 0x0E: OUT_X_DELTA, OUT_Y_DELTA, OUT_Z_DELTA AC Data Registers

X, Y, and Z-axis 8-bit high pass filtered output data is expressed as 2's complement numbers. The data is obtained from the output of the user definable high pass filter. The data cuts out the low frequency data, which is useful in that the offset data is removed. The value of the high pass filter cutoff frequency is set in Register 0x17.

Note: The OUT_X_DELTA, OUT_Y_DELTA, OUT_Z_DELTA registers store the high pass filtered "delta data" information regardless of the state of the FIFO data output register driver bit. Register 0x0B always reflects the status of the delta data.

0x0C OUT_X_DELTA: AC X 8-Bit Data Register (Read Only)

0x0D OUT_Y_DELTA: AC Y 8-Bit Data Register (Read Only)

0x0E OUT_Z_DELTA: AC Z 8-Bit Data Register (Read Only)

0x0F: WHO_AM_I Device ID Register

This register contains the device identifier which for MMA8450Q is set to **0xC6** by default. The value is factory programmed by a byte of NVM. A custom alternate value can be set by customer request.

0x0F WHO_AM_I: Device ID Register (Read Only)

6.2 32 Sample FIFO

The following registers are used to configure the FIFO. The following are the FIFO registers for the MMA8450Q. For more information on the FIFO please refer to AN3920*.*

0x10: F_STATUS FIFO Status Register

The FIFO Status Register is used to retrieve information about the FIFO. This register has a flag for the overflow and watermark. It also has a counter that can be read to obtain the number of samples stored in the buffer.

0x10 F_STATUS: FIFO STATUS Register (Read Only)

Table 13. FIFO Flag Event Description

The F_OVF and F_WMRK_FLAG flags remain asserted while the event source is still active, but the user can clear the FIFO interrupt bit flag in the interrupt source register (INT_SOURCE) by reading the F_STATUS register.

Therefore the F_OVF bit flag will remain asserted while the FIFO has overflowed and the F_WMRK_FLAG bit flag will remain asserted while the F_CNT value is greater than the F_WMRK value.

Table 14. FIFO Sample Count Description

F_CNT[5:0] bits indicate the number of acceleration samples currently stored in the FIFO buffer. Count 000000 indicates that the FIFO is empty.

0x11: F_8DATA 8-Bit FIFO Data

F_8DATA provides access to the previous (up to) 32 samples of X, Y, and Z-axis acceleration data at 8-bit resolution. Use F_12DATA to access the same FIFO data at 12-bit resolution. The advantage of F_8DATA access is much faster download of the sample data, since it is represented by only 3 bytes per sample (OUT_X_MSB, OUT_Y_MSB, and OUT_Z_MSB).

All reads to address 0x01 returns the sensor sampled data in the FIFO buffer, 3 bytes per sample (one byte per axis), with the oldest samples first, in order OUT_X_MSB, OUT_Y_MSB, and OUT_Z_MSB. When all samples indicated by the FIFO_Status register have been read from the FIFO, subsequent reads will return 0x00. Since the FIFO holds a maximum of 32 samples, a maximum of $3 \times 32 = 96$ data bytes of samples can be read.

The FIFO will not accumulate more sample data during an access to F_8DATA until a STOP or repeated START occurs.

0x11 F_8DATA: 8-Bit FIFO Data Register Points to Register 0x01 (Read Only)

The host application should initially perform a single byte read of the FIFO status byte (address 0x10) to determine the status of the FIFO and if it is determined that the FIFO contains data sample(s), the FIFO contents can also be read from register address location 0x01 or 0x05.

0x12: F_12DATA 12-Bit FIFO Data

F 12DATA provides access to the previous (up to) 32 samples of X, Y, and Z-axis acceleration data, at 12-bit resolution. Use F_8DATA to access the same FIFO data at 8-bit resolution. The advantage of F_8DATA access is much faster download of the sample data, since it is represented by only 3 bytes per sample (OUT_X_MSB, OUT_Y_MSB, and OUT_Z_MSB).

When the FDE bit is set to logic 1, the F_12DATA FIFO root data pointer shares the same address location as the OUT X MSB register (0x05); therefore all 12-bit accesses of the FIFO buffer data must use the I^2C register address 0x05. All reads to the register address 0x02, 0x03, 0x06, 0x07, 0x08, 0x09, and 0x0A return a value of 0x00.

All reads from address (0x05) return the sample data, oldest samples first, in order OUT_X_LSB OUT_X_MSB, OUT_Y_LSB, OUT_Y_MSB, OUT_Z_LSB, and OUT_Z_MSB. When all samples indicated by the F_Status byte have been read from the FIFO, subsequent reads will return 0x00. Since the FIFO holds a maximum of 32 samples, a maximum of $6 \times 32 = 192$ data bytes can be read.

The FIFO will not accumulate more sample data during an access to F 12DATA until a STOP or repeated START occurs.

0x12 F_12DATA: 12-Bit FIFO Data Register Points to Register 0x05 (Read Only)

0x13: F_SETUP FIFO Setup Register

This setup register is used to configure the options for the FIFO. The FIFO can operate in 3 states which are defined in the Mode Bits. The watermark bits are configurable to set the number of samples of data to trigger the watermark event flag. The maximum number of samples is 32. For more information on the FIFO configuration refer to AN3920.

0x13 F_SETUP: FIFO Setup Register (Read/Write)

Table 15. F_SETUP Description

1. Bit field can be written in ACTIVE mode.

2. Bit field can be written in STANDBY mode.

3. The FIFO mode (F_MODE) cannot be switched between the two operational modes (01and 10) in Active Mode.

A FIFO sample count exceeding the watermark event does not stop the FIFO from accepting new data. The FIFO update rate is dictated by the selected system ODR. In active mode the ODR is set by the DR register in the CTRL_REG1 register and when Auto-Sleep is active the ODR is set by the ASLP_RATE field in the CTRL_REG1 register.

When a byte is read from the FIFO buffer the oldest sample data in the FIFO buffer is returned and also deleted from the front of the FIFO buffer, while the FIFO sample count is decremented by one. It is assumed that the host application shall use the I²C multi-read transaction to empty the FIFO.

The FIFO mode can be changed while in the active state. The mode must first be disabled F MODE = 00 then the Mode can be changed.

0x14: SYSMOD System Mode Register

The system mode register indicates the current device operating mode. Applications using the Auto-Sleep/Auto-Wake mechanism should use this register to synchronize the application with the device operating mode transitions. The system mode register also indicates the status of the NVM parity error and FIFO gate error flags.

0x14 SYSMOD: System Mode Register (Read Only)

Table 16. SYSMOD Description

The FIFO Gate is set in Register 0x3A for the device configured for Auto-Wake/Sleep mode to allow the buffer to preserve the data without automatically flushing. If the FIFO buffer is not emptied before the arrival of the next sample, then the FGERR bit in register 0x14 is asserted. The FGERR remains asserted as long as the FIFO buffer remains un-emptied. Emptying the FIFO buffer clears the FGERR bit.

0x15: INT_SOURCE System Interrupt Status Register

In the interrupt source register the status of the various embedded features can be determined.The bits that are set (logic '1') indicate which function has asserted an interrupt and conversely the bits that are cleared (logic '0') indicate which function has not asserted or has deasserted an interrupt. The interrupts are rising edge sensitive. The bits are set by a low to high transition and are cleared by reading the appropriate interrupt source register.

0x15 INT_SOURCE: System Interrupt Status Register (Read Only)

Table 17. INT_SOURCE Description

0x16: XYZ_DATA_CFG Sensor Data Configuration Register

The XYZ_DATA_CFG register configures the 3-axis acceleration data and event flag generator based on the ODR.

0x16 XYZ_DATA_CFG: Sensor Data Configuration Register (Read/Write)

Table 18. XYZ_DATA_CFG Description

0x17: HP_FILTER_CUTOFF High Pass Filter Register

This register sets the high-pass filter cut frequency for the detection of instantaneous acceleration. The output of this filter is indicated by the OUT_X_DELTA, OUT_Y_DELTA, and OUT_Z_DELTA registers. The filter cut options change based on the data rate selected as shown in Table 19. For details of implementation on the high pass filter, refer to Freescale application note AN3918.

0x17 HP_FILTER_CUTOFF: High Pass Filter Register (Read/Write)

Table 19. HP_FILTER_CUTOFF Setting Options

6.3 Portrait/ Landscape Embedded Function Registers

For more details on the meaning of the different user configurable settings and for example code refer to Freescale application note AN3915.

0x18: PL_STATUS Portrait/Landscape Status Register

This status register can be read to get updated information on any change in orientation by reading Bit 7, or on the specifics of the orientation by reading Bit0 to Bit 4. The interrupt for the Portrait/landscape detection is cleared by reading the status register. For further understanding of Portrait Up, Portrait Down, Landscape Left, Landscape Right, Back and Front please refer to Figure 3

0x18 PL_STATUS Register (Read Only)

Table 20. PL_STATUS Register Description

1. The default power up state is BAFRO (Undefined), LAPO (Undefined), and no Lockout for orientation function.

NEWLP is set to 1 whenever a change in LO, BAFRO, or LAPO occurs. NEWLP bit is cleared anytime PL_STATUS register is read.

0x19: PL_PRE_STATUS Portrait/Landscape Previous Data Status Register

This register provides the previous orientation data from the previous reading. These register definitions are the same as what has been described in Register 0x18.

0x19 PL_PRE_STATUS Register (Read Only)

0x1A: PL_CFG Portrait/Landscape Configuration Register

This register configures the behavior of the debounce counters and also sets the Landscape/Portrait 1g lockout mechanism threshold offset.

0x1A PL_CFG Register (Read/Write)

Table 21. PL_CFG Register Description

0x1B: PL_COUNT Portrait Landscape Debounce Register

This register sets the debounce counter for the orientation state transition. The minimum debounce latency is determined by the data rate set by the selected system ODR and PL_COUNT registers. Any change to the ODR or device mode transitioning from ACTIVE to STANDBY or vice versa resets the internal landscape/portrait internal debounce counters.

0x1B PL_COUNT Register (Read/Write)

The debounce counter scales with the ODR, like many of the debounce counters in the other functional blocks. Table 22 shows the relationship between the ODR, the step per count and the duration.

Table 22. PL_COUNT Relationship with the ODR

0x1C: PL_BF_ZCOMP Back/Front and Z Compensation Register

The Z-Tilt angle compensation bits allow the user to adjust the Z-lockout region from 25° up to 50°. The default Z-lockout angle is set to the default value of 32 \degree upon power up. The Back to Front trip angle is set by default to $\pm 75\degree$ but this angle also can be adjusted from a range of 65° to 80° with 5° step increments.

0x1C: PL_BF_ZCOMP Register (Read/Write)

Table 23. PL_BF_ZCOMP Description

Table 24. Back/Front Orientation Definitions

0x1D - 0x1F: PL_P_L_THS_REG1, 2, 3 Portrait-to-Landscape Threshold Registers

The following registers represent the Portrait-to-Landscape trip threshold registers. These registers are used to set the trip angle for the image transition from the Portrait orientation to the Landscape orientation. The angle can be selected from Table 28 and the corresponding values for that angle should be written into the three PL_P_L_THS Registers.

0x1D PL_P_L_THS_REG1 Register (Read/Write)

Table 25. PL_P_L_THS_REG1 Description

0x1E PL_P_L_THS_REG2 Register (Read/Write)

Table 26. PL_P_L_THS_REG2 Description

P_L_THS Portrait-to-Landscape Threshold Register 2. Default value: **30°** → **0010_0010**.

0x1F PL_P_L_THS_REG3 Register (Read/Write)

Table 27. PL_P_L_THS_REG3 Description

P_L_THS Portrait-to-Landscape Threshold Register 3. Default value: **30°**→ **1101_0100**.

Table 28. Portrait-to-Landscape Trip Angle Thresholds Lookup Table

0x20 - 0x22 PL_L_P_THS_REG1, 2, 3 Landscape-to-Portrait Threshold Registers

The following registers represent the Landscape-to-Portrait trip threshold registers. These registers are used to set the trip angle for the image transition from the Landscape orientation to the Portrait orientation. The angle can be selected from Table 32 and the corresponding values for that angle should be written into the three PL_L_P_THS Registers.

0x20 PL_L_P_THS_REG1 Register (Read/Write)

Table 29. PL_L_P_THS_REG1 Description

0x21 PL_L_P_THS_REG2 Register (Read/Write)

Table 30. PL_L_P_THS_REG2 Description

L_P_THS Landscape-to-Portrait Threshold Register 2. Default value: **60°** → **0100_0001**.

0x22 PL_L_P_THS_REG3 Register (Read/Write)

Table 31. PL_L_P_THS_REG3 Description

L_P_THS Landscape-to-Portrait Threshold Register 3. Default value: **60°** → **1010_0010**.

Table 32. Landscape-to-Portrait Trip Angle Thresholds Lookup Table

6.4 Freefall & Motion Detection Registers

For details on how to configure the device for Freefall and/or Motion detection and for sample code, refer to application note AN3917.

Note: There are two Freefall and Motion Detection Functions. The registers from 0x27 - 0x2A have the same descriptions as registers 0x23 - 0x26.

0x23: FF_MT_CFG_1 Freefall and Motion Configuration Register 1

0x23 FF_MT_CFG_1 Register (Read/Write)

Table 33. FF_MT_CFG_1 Description

OAE bit allows the selection between Motion (logical OR combination of X, Y, Z-axis event flags) and Freefall (logical AND combination of X, Y, Z-axis event flags) detection.

ELE denotes whether the enabled event flag will be latched in the FF_MT_SRC_1 register or the event flag status in the FF_MT_SRC_1 will indicate the real-time status of the event. If ELE bit is set to a logic 1, then the event active "EA" flag is cleared by reading the FF_MT_SRC_1 source register.

ZHEFE, YHEFE, XHEFE enables the detection of a high g event when the measured acceleration data on X, Y, or Z-axis is higher than the threshold set in FF_MT_THS_1 register.

ZLEFE, YLEFE, XLEFE enables the detection of a low g event when the measured acceleration data on X, Y, or Z-axis is lower than the threshold set in FF_MT_THS_1 register.

FF_MT_THS_1 is the threshold register used by the Freefall/Motion function to detect Freefall or Motion events. The unsigned 7-bit FF_MT_THS_1 threshold register holds the threshold for the low g event detection where the magnitude of the X and Y and Z acceleration values are lower than the threshold value. Conversely the FF_MT_THS_1 also holds the threshold for the high g event detection where the magnitude of the X, or Y, or Z-axis acceleration values is higher than the threshold value.

0x24 FF_MT_SRC_1 Register

0x24: FF_MT_SRC_ Freefall and Motion Source Register (0x24) (Read Only)

Table 34. FF_MT_SRC_1 Description

This register keeps track of the acceleration event which is triggering (or has triggered, in case of ELE bit in FF_MT_CFG_1 register being set to 1) the event flag. In particular EA is set to a logic 1 when the logical combination of acceleration events flags specified in FF_MT_CFG_1 register is true. This bit is used in combination with the values in INT_EN_FF_MT_1 and INT_CFG_FF_MT_1 register to generate the Freefall/Motion interrupts.

An X,Y, or Z high or an X,Y, and Z high event is true when the acceleration value of the X or Y or Z axes is higher than the preset threshold value defined in the FF_MT_THS_1 register.

Conversely X,Y, or Z high or an X,Y, and Z low event is true when the acceleration value of the X and Y and Z axes are lower than the preset threshold value defined in the FF_MT_THS_1 register.

When the ELE bit is set, only the EA bit is latched. The other bits are not latched. To see the events that have been detected, the register must be read immediately. The EA bit will remain high until the source register is read.

0x25: FF_MT_THS_1 Freefall and Motion Threshold 1 Register

0x25 FF_MT_THS_1 Register (Read/Write)

Table 35. FF_MT_THS_1 Description

The minimum threshold resolution is dependent on the selected acceleration g range and the threshold register has a range of 0 to 127.

Therefore:

- If the selected acceleration g range is 8g mode ($FS = 11$), the minimum threshold resolution is 0.063g/LSB. The maximum value is 8g.
- If the selected acceleration g range is 4g mode ($FS = 10$), the minimum threshold resolution is 0.0315g/LSB. The maximum value is 4g.
- If the selected acceleration g range is 2g mode ($FS = 01$), the minimum threshold resolution is 0.01575g/LSB. The maximum value is 2g.

When DBCNTM bit is a logic '1', the debounce counter is cleared to 0 whenever the event of interest is no longer true (Figure 12 part b) while if the DBCNTM bit is set a logic '0' the debounce counter is decremented by 1 whenever the event of interest is no longer true (Figure 12 part c) until the debounce counter reaches 0 or the event of interest becomes active.

Decrementing of the debounce counter acts as a median filter enabling the system to filter out irregular spurious events which might impede the detection of the event.

0x26: FF_MT_COUNT_1 Freefall Motion Count 1 Register

This register sets the number of debounce sample counts for the event trigger.

0x26 FF_MT_COUNT_1 Register (Read/Write)

Table 36. FF_MT_COUNT_1 Description

D7 - D0 define the number of debounce sample counts for the event trigger. When the debounce counter exceeds the FF_MT_COUNT_1 value, a Freefall/Motion event flag is set. The time step used for the debounce sample count depends on the ODR chosen (Table 37).

Table 37. FF_MT_COUNT_1 and FF_MT_COUNT_2 Relationship with the ODR

An ODR of 100 Hz and a FF_MT_COUNT_1 value of 15 would result in a debounce response time of 150 ms.

0x27: FF_MT_CFG_2 Freefall and Motion Configuration 2 Register

These registers all have the same descriptions as above for Registers 0x23 - 0x26.

0x27 FF_MT_CFG_2 Register (Read/Write)

0x28: FF_MT_SRC_2 Freefall and Motion Source 2 Register

0x28 FF_MT_SRC_2 Register (Read Only)

0x29: FF_MT_THS_2 Freefall and Motion Threshold 2 Register

0x29 FF_MT_THS_2 Register (Read/Write)

0x2A: FF_MT_COUNT_2 Freefall and Motion Debounce 2 Register

0x2A FF_MT_COUNT_2 Register (Read/Write)

6.5 Transient Detection Registers

For more information on the uses of the transient function and sample code, refer to application note AN3918.

0x2B: TRANSIENT_CFG Transient Configuration Register

The transient detection mechanism can be configured to raise an interrupt when the magnitude of the high pass filtered data is greater than a user definable threshold. The TRANSIENT CFG register is used to enable the transient interrupt generation mechanism for each of the 3 axes (X, Y, Z) of acceleration.

0x2B TRANSIENT_ CFG Register (Read/Write)

Table 38. TRANSIENT_ CFG Description

0x2C: TRANSIENT_SRC Transient Source Register

The transient source register is read to determine the source of an interrupt. When the ELE bit is set in Register0x2B the "EA" event Active bit in the source register is latched. The other bits in the source register are not latched. The source register must be read immediately following the interrupt to determine the axes the event occurred on. The interrupt for the transient event is cleared by reading the status register.

0x2C TRANSIENT_SRC Register (Read Only)

Table 39. TRANSIENT_SRC Description

0x2D: TRANSIENT_THS Transient Threshold Register

The TRANSIENT_THS register sets the threshold limit for the high pass filtered acceleration. The value in the TRANSIENT_THS register corresponds to a g value which is compared against the values of OUT_X_DELTA, OUT_Y_DELTA, and OUT_Z_DELTA. If the acceleration exceeds the threshold limit an event flag is raised and an interrupt is generated if interrupts are enabled.

0x2D TRANSIENT_THS Register (Read/Write)

Table 40. TRANSIENT_THS Description

The minimum threshold resolution is dependent on the selected acceleration g range and the threshold register has a range of 0 to 127.

Therefore:

- \cdot If the selected acceleration g range is 8g mode (FS = 11), the minimum threshold resolution is 0.063g/LSB. The maximum is 8g.
- If the selected acceleration g range is 4g mode (FS = 10), the minimum threshold resolution is 0.0315g/LSB. The maximum is 4g.
- If the selected acceleration g range is 2g mode ($FS = 01$), the minimum threshold resolution is 0.01575g/LSB. The maximum is 2g.
- The DBCNTM bit behaves in the same manner described previously for the Motion/Freefall 1.

0x2E: TRANSIENT_COUNT Transient Debounce Register

The TRANSIENT_COUNT sets the minimum number of debounce counts continuously matching the condition where the unsigned value of OUT_X_DELTA or OUT_Y_DELTA or OUT_Z_DELTA register is greater than the user specified value of TRANSIENT_THS.

0x2E TRANSIENT_COUNT Register (Read/Write)

Table 41. TRANSIENT_COUNT Description

The time step for the Transient detection debounce counter is set by the value of the system ODR.

Table 42. TRANSIENT_COUNT Relationship with the ODR

An ODR of 100 Hz and a TRANSIENT_COUNT value of 15 would result in a debounce response time of 150 ms.

6.6 Tap Detection Registers

For more details of how to configure the tap detection and sample code please refer to Freescale application note, AN3919. The tap detection registers are referred to as "Pulse".

0x2F: PULSE_CFG Pulse Configuration Register

This register configures the event flag for the tap detection for enabling/disabling the detection of a single and double pulse on each of the axes.

0x2F PULSE_CFG Register (Read/Write)

Table 43. PULSE_CFG Description

0x30: PULSE_SRC Pulse Source Register

This register indicates a double or single pulse event has occurred. The corresponding axis and event must be enabled in Register 0x2F for the event to be seen in the source register. The interrupt for the pulse event is cleared by reading the status register.

0x30 PULSE_SRC Register (Read Only)

Table 44. TPULSE_SRC Description

0x31 - 0x33: PULSE_THSX, Y, Z Pulse Threshold for X, Y & Z Registers

The pulse threshold can be set separately for the X, Y and Z axes. The threshold values range from 0 to 31 counts with steps of 0.258g/LSB **at a fixed 8g acceleration range**, thus the minimum resolution is always fixed at 0.258g/LSB irrespective of the selected g range.

The PULSE_THSX, PULSE_THSY and PULSE_THSZ registers define the threshold which is used by the system to start the pulse detection procedure. The threshold value is expressed over 5-bits as an unsigned number.

0x31 PULSE_THSX Register (Read/Write)

Table 45. PULSE_THSX Description

0x32 PULSE_THSY Register (Read/Write)

Table 46. PULSE_THSY Description

0x33 PULSE_THSZ Register (Read/Write)

Table 47. PULSE_THSZ Description

THSZ4, THSZ0 | Pulse Threshold on Z-axis. Default value: 0_0000.

0x34: PULSE_TMLT Pulse Time Window 1 Register

0x34 PULSE_TMLT Register (Read/Write)

The bits Tmlt7 through Tmlt0 define the maximum time interval that can elapse between the start of the acceleration on the selected axis exceeding the specified threshold and the end when the acceleration on the selected axis must go below the specified threshold to be considered a valid pulse.

The minimum time step for the pulse time limit is defined in Table 48. Maximum time for a given ODR is the minimum time step at the given power mode multiplied by 255. The time steps available are dependent on whether the device is in Normal Power mode or in Low Power mode. Notice in the table below that the time step is twice as long in Low Power mode.

Table 48. Time Step for PULSE Time Limit at ODR and Power Mode

Therefore an ODR setting of 400 Hz with normal power mode would result in a maximum pulse time limit of (0.625 ms * 255) ≥ 159 ms.

0x35: PULSE_LTCY Pulse Latency Timer Register

0x35 PULSE_LTCY Register (Read/Write)

The bits Ltcy7 through Ltcy0 define the time interval that starts after the first pulse detection. During this time interval, all pulses are ignored. **Note:** This timer must be set for single pulse and for double pulse.

The minimum time step for the pulse latency is defined in Table 49. The maximum time is the time step at the ODR and Power Mode multiplied by 255. Notice that the time step is twice the duration if the device is operating in Low Power mode, as shown below.

Table 49. Time Step for PULSE Latency at ODR and Power Mode

0x36: PULSE_WIND Second Pulse Time Window Register

0x36 PULSE_WIND Register (Read/Write)

The bits Wind7 through Wind0 define the maximum interval of time that can elapse after the end of the latency interval in which the start of the second pulse event must be detected provided the device has been configured for double pulse detection. The detected second pulse width must be shorter than the time limit constraints specified by the PULSE_TMLT register, but the end of the double pulse need not finish within the time specified by the PULSE_WIND register.

The minimum time step for the pulse window is defined in Table 50. The maximum time is the time step at the ODR and Power Mode multiplied by 255.

Table 50. Time Step for PULSE Detection Window at ODR and Power Mode

6.7 Auto-Sleep Registers

For additional information on how to configure the device for the Auto-Sleep/Wake feature, refer to AN3921.

0x37: ASLP_COUNT Auto-Sleep Inactivity Timer Register

The ASLP_COUNT register sets the minimum time period of inactivity required to change current ODR value from the value specified in the **DR[2:0]** to **ASLP_RATE** (Reg 0x38) value provided the **SLPE** bit is set to a logic '1' in the **CTRL_REG2** register.

0x37 ASLP_COUNT Register (Read/Write)

Table 51. ASLP_COUNT Description

D7-D0 defines the minimum duration time to change current ODR value from **DR** to **ASLP_RATE**. Time step and maximum value depend on the ODR chosen (see Table 52).

Table 52. ASLP_COUNT Relationship with ODR

In order to wake the device, the desired function or functions must be enabled and set to "Wake From Sleep". All enabled functions will still function in sleep mode at the sleep ODR. Only the functions that have been selected for "Wake From Sleep" will **wake** the device.

MMA8450Q has 6 functions that can be used to keep the sensor from falling asleep namely, Transient, Orientation, Tap, Motion/FF1 and Motion/FF2 and the FIFO. One or more of these functions can be enabled. In order to wake the device, functions are provided namely, Transient, Orientation, Tap, and the two Motion/Freefall. Note that the FIFO does not wake the device. The Auto-Wake/Sleep interrupt does not affect the wake/sleep, nor does the data ready interrupt. The FIFO gate (bit 7) in Register 0x3A, when set, will hold the last data in the FIFO before transitioning to a different ODR. After the buffer is flushed, it will accept new sample data at the current ODR. See Register 0x3A for the wake from sleep bits.

If the Auto-Sleep bit is disabled, then the device can only toggle between Standby and Wake Mode by writing to the FS0 and FS1 bits in Register 0x38 CTRL_REG1. If Auto-Sleep interrupt is enabled, transitioning from Active mode to Auto-Sleep mode and vice versa generates an interrupt.

0x38: CTRL_REG1 System Control 1 Register

0x38 CTRL_REG1 Register (Read/Write)

Table 53. CTRL_REG1 Description

Table 54. Sleep Mode Poll Rate Description

It is important to note that when the device is in Auto-Sleep mode, the system ODR and the data rate for all the system functional blocks are overwritten by the data rate set by the **ASLP_RATE** field in Register 0x38.

DR[2:0] bits select the output data rate (ODR) for acceleration samples. The default value is 000 for a data rate of 400 Hz.

Table 55. System Output Data Rate Selection

Table 55. System Output Data Rate Selection

FS[1:0] bits select between standby mode and active mode. The default value is 00 for standby mode.

Table 56. Full Scale Selection

0x39: CTRL_REG2 System Control 2 Register

0x39 CTRL_REG2 Register (Read/Write)

Table 57. CTRL_REG2 Description

1. When SLPE = 1, the transitioning between sleep mode and wake mode results in a FIFO flush and a reset of internal functional block counters. All functional block status information are preserve except otherwise stated. See Table 58 for more information about the FIFO_GATE bit in CTRL_REG3 register.

ST bit activates the Self-Test function. When ST is set to one, an output change will occur to the device outputs (refer to Table 2 and Table 3) thus allowing host application to check the functionality of the entire signal chain.

BOOT bit is used to activate the software reset. The Boot mechanism can be enabled in STANDBY and ACTIVE mode.

When the Boot bit is enabled the Boot mechanism resets all functional block registers and loads the respective internal registers with default NVM values.

The system will automatically transition to standby mode if not already in standby mode before the software reset (re-BOOT process) can occur.

Note: The I²C communication system is reset to avoid accidental corrupted data access.

0x3A: CTRL_REG3 Interrupt Control Register

0x3A CTRL_REG3 Register (Read/Write)

Table 58. CTRL_REG3 Description

IPOL bit selects the polarity of the interrupt signal. When IPOL is '0' any interrupt event will signalled with a logical 0. **PP_OD** bit configures the interrupt pin to Push-Pull or in Open Drain mode. The open drain configuration can be used for connecting multiple interrupt signals on the same interrupt line.

0x3B: CTRL_REG4 Register (Read/Write)

0x3B CTRL_REG4 Register (Read/Write)

Table 59. interrupt Enable Register Description

The corresponding functional block interrupt enable bit allows the functional block to route its event detection flags to the system's interrupt controller. The interrupt controller routes the enabled functional block interrupt to the INT1 or INT2 pin.

0x3C: CTRL_REG5 Interrupt Configuration Register

0x3C CTRL_REG5 Register (Read/Write)

Table 60. Interrupt Configuration Register Description

The system's interrupt controller shown in Figure 10 uses the corresponding bit field in the CTRL_REG5 register to determine the routing table for the INT1 and INT2 interrupt pins. If the bit value is logic '0' the functional block's interrupt is routed to INT2, and if the bit value is logic '1' then the interrupt is routed to INT1. One or more functions can assert an interrupt pin; therefore a host application responding to an interrupt should read the INT_SOURCE (0x15) register to determine the appropriate sources of the interrupt.

6.8 User Offset Correction Registers

For more information on how to calibrate the 0g Offset refer to AN3916 Offset Calibration Using the MMA8450Q. The 2's complement offset correction registers values are used to realign the Zero-g position of the X, Y, and Z-axis after device board mount. The resolution of the offset registers is 3.906 mg per LSB. The 2's complement 8-bit value would result in an offset compensation range ±0.5g.

0x3D: OFF_X Offset Correction X Register

0x3D OFF_X Register (Read/Write)

Table 61. OFF_X Description

0x3E: OFF_Y Offset Correction Y Register

0x3E OFF_Y Register (Read/Write)

Table 62. OFF_Y Description

D7-D0 | Y-axis offset trim LSB value. Default value: 0000_0000.

0x3F: OFF_Z Offset Correction Z Register

0x3F OFF_Z Register (Read/Write)

Table 63. OFF_Z Description

Appendix A

Table 64. MMA8450Q Register Map

Table 64. MMA8450Q Register Map

Table 65. Accelerometer Output Data

Appendix B

Figure 13. Distribution of Pre Board Mounted Devices Tested in Sockets (1 count = 3.9 mg)

89

Distributions

Quantiles

Momente

⊂∍

Post BM Z 0g Offset

Figure 14. Distribution of Post Board Mounted Devices (1 count = 3.9 mg)

Moments

Figure 15. 2g/4g/8g X-axis TCS (%/°C)

%/C X Axis Sense 85C

Quantiles

Moments Mean 0.0052493 Std Dev 0.0085428 Std Err Mean 0.0007932 Upper 95% Mean 0.0068205 Lower 95% Mean 0.0036782 N 116

0.0591

0.0591

Figure 16. 2g/4g/8g Y-axis TCS (%/°C)

Upper 95% Mean

Lower 95% Mean

N

 $\boldsymbol{0}$

0

115

N

Upper 95% Mean

Lower 95% Mean

0.0059311

0.0025701

115

Figure 17. 2g/4g/8g Z-axis TCS (%/°C)

%/C Z Axis Sense 85C

Quantiles

mg/C X Axis Offset 85C

×

Figure 18. 2g/4g/8g X-axis TCO (mg/°C)

Distributions

mg/C Y Axis Offset 85C

Quantiles

Moments	
Mean	0.1605936
Std Dev	0.3231423
Std Err Mean	0.0301332
Upper 95% Mean	0.2202872
Lower 95% Mean	0.1009
	115

Figure 19. 2g/4g/8g Y-axis TCO (mg/°C)

Distributions

Quantiles

Moments

mg/C Z Axis Offset 25C

Quantiles

Moments

Figure 20. 2g/4g/8g Z-axis TCO (mg/°C)

mg/C Z Axis Offset 85C

Quantiles

PACKAGE DIMENSIONS

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DETAIL G

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PACKAGE DIMENSIONS

NOTES:

- 1. ALL DIMENSIONS ARE IN MILLIMETERS.
- 2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M-1994.
- 3. THIS IS NON JEDEC REGISTERED PACKAGE.

 $\sqrt{4}$ coplanarity applies to all leads.

5. MIN. METAL GAP SHOULD BE 0.2MM.

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Revision History

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